



40V N+N-Channel Enhancement Mode MOSFET

40V/10A, R _{DS(ON)}=16mΩ (typ.)@VGS= 10V

40V/7.0A, R_{DS(ON)}=20mΩ (typ.)@VGS= 4.5V

■ FEATURE



Description

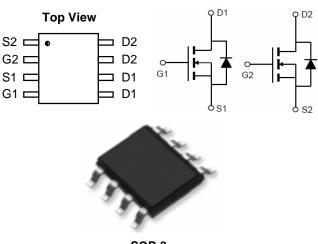
The XPX4099XS uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



SOP-8

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
XPX4099XS	XPX4099XS	SOP-8	Ø330mm	12mm	3000 units

Absolute Maximum Ratings (T_A=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	Vds	40	V
Gate-Source Voltage	V _{GS}	±20	V
Drain Current-Continuous	Ι _D	10	А
Drain Current-Continuous(T _C =100℃)	I _D (100℃)	7.0	A
Pulsed Drain Current	I _{DM}	38	A
Maximum Power Dissipation	PD	2.5	W
Operating Junction and Storage Temperature Range	T_{J},T_{STG}	-55 To 150	°C
Thermal Resistance, Junction-to-Ambient (Note 2)	R _{eJA}	65	°C /W



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Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	40			V	
∆BVbss/∆Tj	BVDSS Temperature Coefficient	Reference to 25°C , I _D =1mA		0.032		V/°C	
		V _{GS} =10V , I _D =7A		16	20		
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =4.5V , I _D =6A		20	26	mΩ	
VGS(th)	Gate Threshold Voltage		1.2	1.6	2.5	V	
extstyle VGS(th)	V _{GS(th)} Temperature Coefficient	V _{GS} =V _{DS} , I _D =250uA		-4.8		mV/°C	
		V _{DS} =32V , V _{GS} =0V , T _J =25°C			1		
loss	Drain-Source Leakage Current	V _{DS} =32V , V _{GS} =0V , T _J =55°C			5	uA	
lgss	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA	
gfs	Forward Transconductance	V _{DS} =5V , I _D =7A		32		S	
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		2.1			
Qg	Total Gate Charge (4.5V)			9.8			
Qgs	Gate-Source Charge			2.8		nC	
Qgd	Gate-Drain Charge	-		3.9			
Td(on)	Turn-On Delay Time			2.8			
Tr	Rise Time			40.4			
Td(off)	Turn-Off Delay Time	I _D =7A		22.8		ns	
T _f	Fall Time	-		6.4			
Ciss	Input Capacitance			1013			
Coss	Output Capacitance			107		pF	
Crss	Reverse Transfer Capacitance	-		76			
ls	Continuous Source Current ^{1,5}				8	A	
lsм	Pulsed Source Current ^{2,5}	──V _G =V _D =0V , Force Current			36	А	
Vsd	Diode Forward Voltage ²	V _{GS} =0V , I _S =1A , T _J =25°C			1	V	
trr	Reverse Recovery Time	I⊧=7A , dl/dt=100A/µs ,		10		nS	
Qrr	Reverse Recovery Charge	TJ=25°C		3.3		nC	

Note :

1. The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width $\,\leq\,$ 300us , duty cycle $\,\leq\,$ 2%

3. The EAS data shows Max. rating . The test condition is V_{DD} =25V, V_{GS} =10V, L=0.1mH, I_{AS}=25A

4.The power dissipation is limited by 150°C junction temperature

5. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



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Typical Characteristics

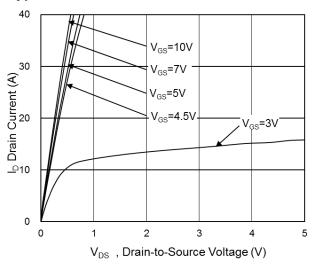


Fig.1 Typical Output Characteristics

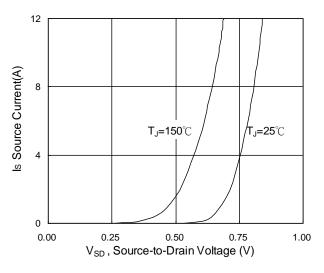


Fig.3 Forward Characteristics of Reverse

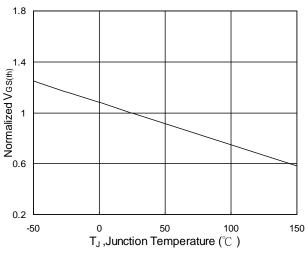


Fig.5 Normalized $V_{GS(th)}$ vs. T_J



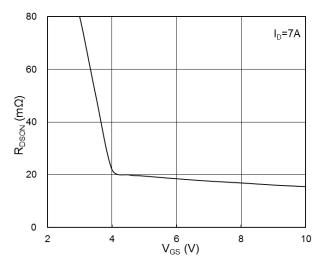


Fig.2 On-Resistance vs. G-S Voltage

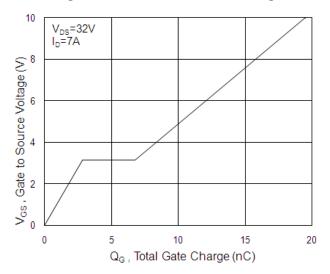


Fig.4 Gate-Charge Characteristics

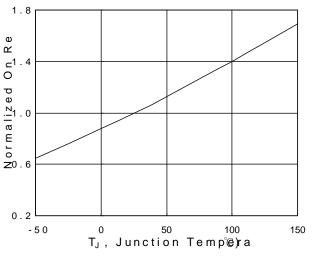
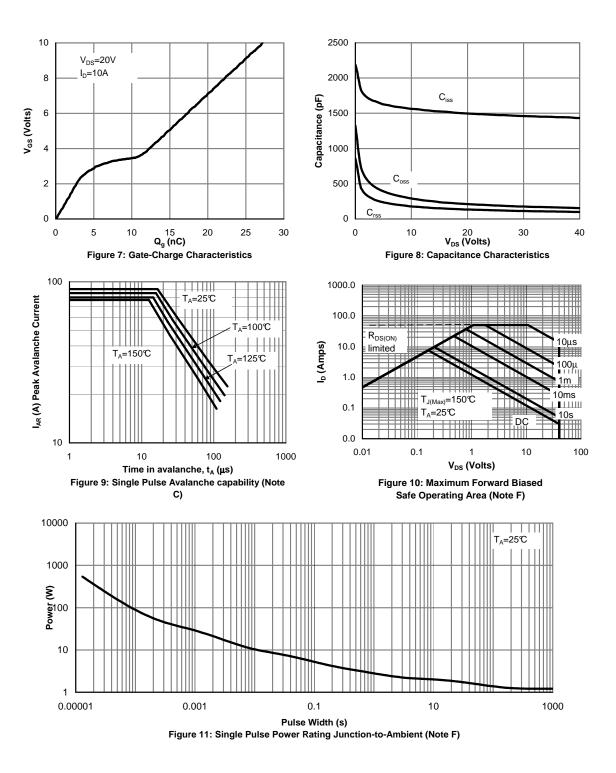


Fig.6 Normalized R_{DSON} vs. T_J



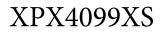
XPX4099XS

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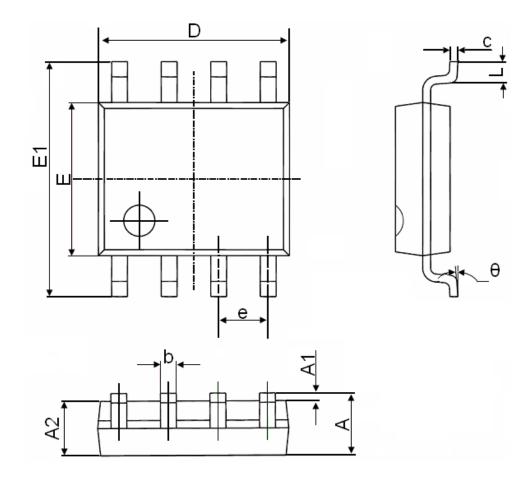


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SOP-8 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
A	1.350	1.750	0.053	0.069	
A1	0.100	0.250	0.004	0.010	
A2	1.350	1.550	0.053	0.061	
b	0.330	0.510	0.013	0.020	
С	0.170	0.250	0.006	0.010	
D	4.700	5.100	0.185	0.200	
E	3.800	4.000	0.150	0.157	
E1	5.800	6.200	0.228	0.244	
е	1.270(BSC)		0.050(BSC)		
L	0.400	1.270	0.016	0.050	
θ	0°	8°	0°	8°	



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Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245℃±5℃	5sec±1sec
Pb-Free device	260 ℃ +0/-5 ℃	5sec±1sec



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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